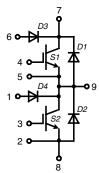


XPT IGBT phaseleg ISOPLUSTM Surface Mount Power Device



IGBTs S1, S2							
Symbol	Conditions	Maximum Ratings					
V _{CES}	$T_{VJ} = 25^{\circ}C$ to $150^{\circ}C$	1200	V				
V _{GES}		±20	V				
I _{C25} I _{C80}	$T_{c} = 25^{\circ}C$ $T_{c} = 80^{\circ}C$	63 45	A A				
I _{CM} V _{CEK}	$V_{GE} = 15 \text{ V}; R_G = 27 \Omega; T_{VJ} = 125^{\circ}\text{C}$ RBSOA, clamped inductive load; L = 100 µH	105 V _{ces}	Α				
t _{sc} (SCSOA)	V_{CE} = 900 V; V_{GE} = ±15 V; R_G = 27 Ω ; T_{VJ} = 125°C none repetitive	10	μs				
P _{tot}	T _{vJ} = 25°C	230	W				

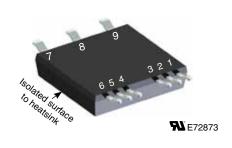
Symbol Conditions

Characteristic **Values**

 $(T_{VJ} = 25^{\circ}C, \text{ unless otherwise specified})$

		min.	typ.	max.	
V _{CE(sat)}	$I_C = 35 \text{ A}; V_{GE} = 15 \text{ V}; T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 125^{\circ}\text{C}$		1.85 2.2	2.15	V
$V_{\text{GE(th)}}$	$I_C = 1.5 \text{ mA}; V_{GE} = V_{CE}$	5.4		6.5	٧
I _{CES}	$V_{CE} = V_{CES}; V_{GE} = 0 \text{ V}; T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 125^{\circ}\text{C}$		0.25	0.15	mA mA
I _{GES}	$V_{CE} = 0 V_{;} V_{GE} = \pm 20 V$			200	nA
$\begin{array}{c} \mathbf{t_{d(on)}} \\ \mathbf{t_r} \\ \mathbf{t_{d(off)}} \\ \mathbf{t_f} \\ \mathbf{E_{on}} \\ \mathbf{E_{off}} \end{array}$	Inductive load; T_{VJ} = 125°C V_{CE} = 600 V; I_{C} = 35 A V_{GE} = ±15 V; R_{G} = 27 Ω		70 40 250 100 3.8 4.1		ns ns ns ns mJ
C _{ies}	$V_{CE} = 25 \text{ V}; V_{GE} = 0 \text{ V}; f = 1 \text{ MHz}$ $V_{CE} = 600 \text{ V}; V_{GE} = 15 \text{ V}; I_{C} = 35 \text{ A}$		tbd 107		pF nC
R _{thJC}	with heatsink compound (IXYS test setup)		0.75	0.55 0.95	K/W K/W

63 A L_{C25} = 1200 V $V_{CE(sat) typ} = 1.85 V$



Features

XPT IGBT

- low saturation voltage
- positive temperature coefficient for easy paralleling
- fast switching
- short tail current for optimized performance in resonant circuits

• Sonic™ diode

- fast reverse recovery
- low operating forward voltage - low leakage current

V_{CEsat} detection diode

- integrated into package
- very fast diode

• Package

- isolated back surface
- low coupling capacity between pins and heatsink
- PCB space saving
- enlarged creepage towards heatsink
- application friendly pinout
- low inductive current path
- high reliability

Applications

Phaseleg

- buck-boost chopper

• Full bridge

- power supplies
- induction heating
- four quadrant DC drives
- controlled rectifier

• Three phase bridge

- AC drives
- controlled rectifier



setup)

 V_{R}

 $T_C = 25^{\circ}C$ to $150^{\circ}C$

Symbol Conditions Characteristic Values $(T_{VJ} = 25^{\circ}C, \text{ unless otherwise specified})$

typ. max. V_{F} $I_{\rm F} = 35 \, {\rm A}$ $T_{VJ} = 25^{\circ}C$ 2.1 2.4 ٧ $T_{VJ} = 125^{\circ}C$ 2.1 ٧ \mathbf{I}_{RM} Α 30 $I_F = 35 \text{ A}; R_G = 27 \Omega; T_{VJ} = 125^{\circ}\text{C}$ 350 ns $V_R = 600 \text{ V}; V_{GE} = -15 \text{ V}$ tbd E_{rec} mJ K/W R_{thJC} per diode 0.9 R_{thJH} with heatsink compound (IXYS test 1.2 1.5 K/W

Diodes D3, D4 Symbol Conditions Maximum Ratings

Symbol Conditions Characteristic Values

 $(T_{VJ} = 25^{\circ}C, \text{ unless otherwise specified})$

1200

			min.	typ.	max.	
V _F	$I_F = 1 A$	$T_{VJ} = 25^{\circ}C$		1.7	2.2	V
		$T_{VJ} = 125^{\circ}C$		1.5		V
I _R	V _B = 1200 V	T _{v,i} = 25°C			2	μA
		$T_{VJ} = 125^{\circ}C$		30		μA
I _{RM}	$I_F = 1 \text{ A}; di_F/dt = -100 \text{ A/}\mu\text{s}; T_{VJ} = 25^{\circ}\text{C}$			2.3		A
t _{rr}	$\int V_{R} = 100 \text{ V}; V_{GE} =$	0 V		40		ns

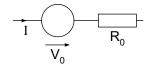
Component **Symbol Conditions Maximum Ratings** T_{VJ} -55...+150 °C °C -55...+125 $\mathsf{T}_{\mathsf{stg}}$ V_{ISOL} 2500 ٧~ $I_{ISOL} \le 1 \text{ mA}; 50/60 \text{ Hz}$ 40 ... 130 \mathbf{F}_{c} mounting force Ν

Symbol	Conditions	Characteristic Values			
		min.	typ.	max.	
C _P	coupling capacity between shorted pins and backside metal		90		pF
d _{s,} d _A d _{s,} d _A	pin - pin pin - backside metal	1.65 4			mm mm
СТІ		400			
Weight			8		g

Ordering	Ordering Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	IXA 40PG1200DHGLB	IXA40PG1200DHGLB	Tape&Reel	200	tbd

Equivalent Circuits for Simulation

Conduction

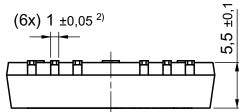


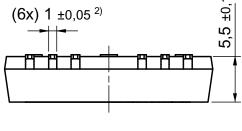
IGBTs (typ. at $V_{GE} = 15 \text{ V}$; $T_J = 125^{\circ}\text{C}$) S1, S2 $V_0 = 1.1 \text{ V}$; $R_0 = 40 \text{ m}\Omega$

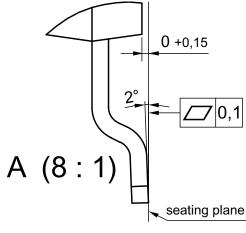
Diodes (typ. at $T_J = 125$ °C) D1, D2 $V_0 = 1.3 \text{ V}; R_0 = 28 \text{ m}\Omega$

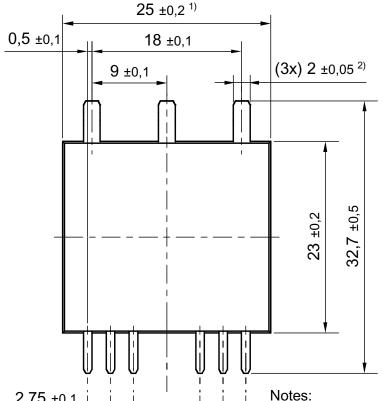


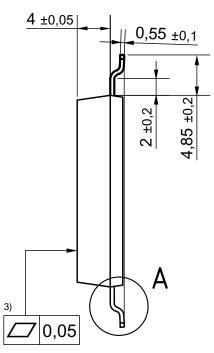
Dimensions in mm (1 mm = 0.0394")











2,75 ±0,1 $5,5 \pm 0,1$ 13,5 ±0,1 16,25 ±0,1

- 1) potrusion may add 0.2 mm max. on each side
- 2) additional max. 0.05 mm per side by punching misalignement or overlap of dam bar or bending compression
- 3) DCB area 10 to 50 µm convex; position of DCB area in relation to plastic rim: ±25 µm (measured 2 mm from Cu rim)
- 4) terminal plating: 0.2 1 μm Ni + 10 25 μm Sn (gal v.) cutting edges may be partially free of plating

19 ±0,1